

Quarterly Reliability Monitoring Results

Quarters: Q1/2023 to Q4/2024

Based on structural similarity

Supplier	User Part Number	
Nexperia B.V.	BZX84-C2V7-Q	
Name of Laboratory	Part Description	
Assembly reliability labs	Nexperia DHAM Zener SMD package	
Based on AEC-Q101 Test	Test Conditions	Duration # Lots # Quantity # Rejects
# E1	TEST Pre- and Post-Stress Electrical Test Tamb = 25 °C	N/A see below all parts see below
# A1	PC Preconditioning JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering	24 hours 168 hours 3 cycles 1602 61540 0
# B1	HTRB High Temperature Reverse Bias MIL-STD-750-1 M1038 Method A Tj = Tjmax, VR = 80 % of rated reverse voltage	1000 hours 256 10240 0
# B1b	SSOP Steady State Operational MIL-STD-750-1 M1038 Method B Tj = Tjmax, Iz = 100% of max. datasheet reverse current	1000 hours 51 2040 0
# A4	TC Temperature Cycling JESD22-A104 -65 °C to Tjmax, not to exceed 150°C	1000 cycles 337 13480 0
# A3 or	UHAST Unbiased HAST JESD22-A118 Tamb = 130 °C, RH = 85 %	96 hours 337 13480 0
# A3 alt	AC Autoclave JESD22-A102 Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)	
# A2 alt	H3TRB High Humidity High Temperature Reverse Bias JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of rated reverse voltage ^[1]	1000 hours 337 13480 0
# A5	IOL Intermittent Operating Life MIL-STD-750 Method 1037 ton = toff, devices powered to insure ΔTj = 100 °C for 15000 cycles	1000 hours 337 13480 0
# C8	RSH Resistance to Solder Heat JESD22-A111 260 °C ± 5 °C	10 s 254 7620 0
# C10	SD Solderability J-STD-002	19 6300 0

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia DHAM	Zener	10240	0	0,41	2,41E+09

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